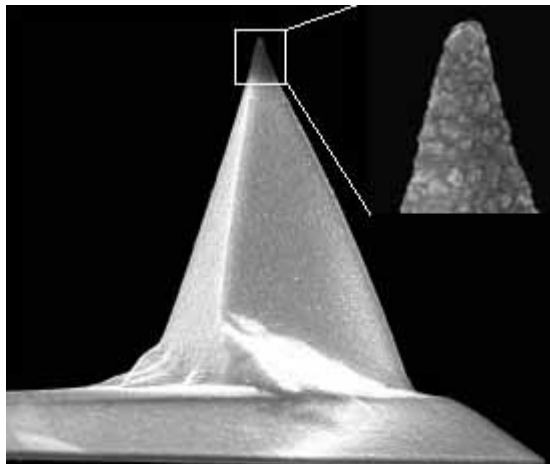


DD-FORTA

The DD-FORTA Probe offers a unique combination of hardness and conducting tip. The tip side of these probes is coated with polycrystalline diamond. The diamond film is in-situ doped with boron to make it highly conducting. The reflex side of the cantilever is coated with Aluminum. These probes are based on the Applied nanostructures FORTA probes which are silicon probes designed for Force Modulation applications. These probes have a medium frequency and spring constant that make them ideally suited to Force Modulation Microscopy, and have Aluminum coating on the reflex side to increase laser signal quality.

Tip Specifications

- **Material:** Silicon
- **Shape:** Pyramidal
- **Height (μm):** 14-16
- **Aspect ratio:** 1.5-3.0
- **ROC (nm) :** 100-300
- **Coating:** 100nm Doped Diamond



DD-FORTA

On click zoom images

Download Spec

Cantilever Specifications

Material: Silicon

Shape : Rectangular

Reflex coating : Al, 50 nm \pm 5

| Parameter | Nominal | Min | Max |
|-----------------------------|---------|-------|-------|
| k (N/m) | 3.0 | 1.2 | 6.4 |
| f (kHz) | 62.0 | 47.0 | 76.0 |
| Length (μm) | 225.0 | 215.0 | 235.0 |
| Width (μm) | 30.0 | 25.0 | 35.0 |
| Thickness (μm) | 3.00 | 2.50 | 3.50 |